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(54) **METHOD FOR VERIFYING AND IMPROVING RUN-TIME OF A MEMORY TEST**

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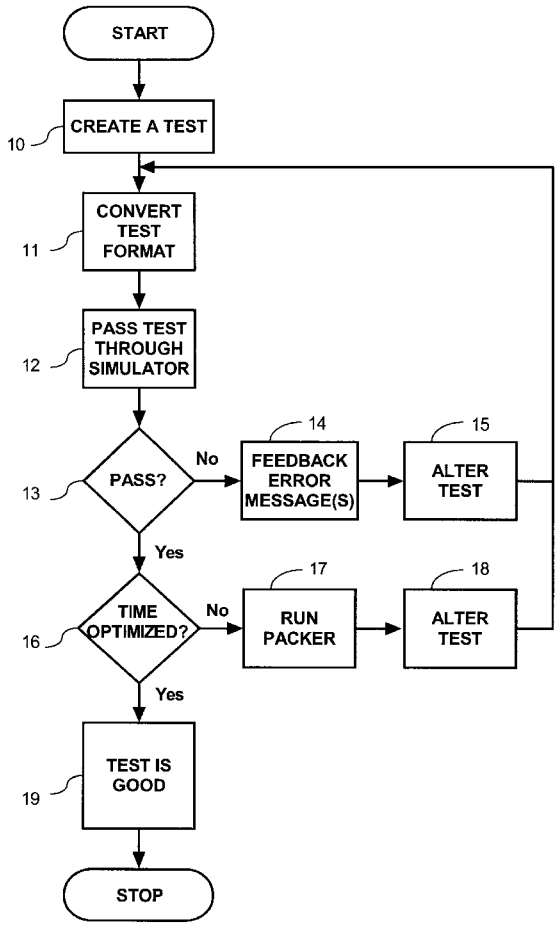
(57) **ABSTRACT**

A method of generating and verifying a memory test is disclosed. A simulator is used to verify that the sequence of time-ordered commands complies with a set of operating constraints for the memory. A packer may thereafter be used to optimize run time of the verified test.

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